

STB21NK50Z

N-channel 500 V, 0.23 Ω, 17 A, D²PAK Zener-protected superMESH™ Power MOSFET

Features

Туре	V _{DSS}	R _{DS(on)} max	I _D	Pw
STB21NK50Z	500 V	< 0.27 Ω	17 A	190 W

- Extremely high dv/dt capability
- 100% avalanche tested
- Gate charge minimized
- Very low intrinsic capacitances
- Very good manufacturing repeatability

Applications

- Switching applications
 - Automotive



The SuperMESH™ series is obtained through an extreme optimization of ST's well established strip-based PowerMESH™ layout. In addition to pushing on-resistance significantly down, special care is taken to ensure a very good dv/dt capability for the most demanding applications.

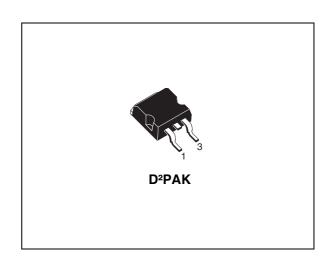


Figure 1. Internal schematic diagram

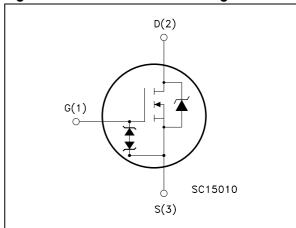


Table 1. Device summary

Order code	Marking	Package	Packaging
STB21NK50Z	21NK50Z	D ² PAK	Tape and reel

Contents STB21NK50Z

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STB21NK50Z Electrical ratings

1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage (V _{GS} = 0)	500	V
V _{GS}	Gate-source voltage	± 30	V
I _D	Drain current (continuous) at $T_C = 25$ °C	17	Α
I _D	Drain current (continuous) at T _C =100 °C	10.71	Α
I _{DM} ⁽¹⁾	Drain current (pulsed)	68	Α
P _{TOT}	Total dissipation at T _C = 25 °C	190	W
	Derating Factor	1.51	W/°C
Vesd(G-S)	G-S ESD (HBM C=100 pF, R=1.5 kΩ)	6000	V
dv/dt ⁽²⁾	Peak diode recovery voltage slope	4.5	V/ns
T _{stg}	Storage temperature	-55 to 150	°C
TJ	Max operating junction temperature	150	°C

^{1.} Pulse width limited by safe operating area

Table 3. Thermal data

Symbol	Parameter	Value	Unit
R _{thj-case}	Thermal resistance junction-case max	0.66	°C/W
R _{thj-amb}	Thermal resistance junction-ambient max	62.5	°C/W
T _I	Maximum lead temperature for soldering purpose	300	°C

Table 4. Avalanche characteristics

Symbol	Parameter	Value	Unit
I _{AR}	Avalanche current, repetitive or not-repetitive (pulse width limited by Tj Max)	17	А
E _{AS}	Single pulse avalanche energy (starting T _J =25 °C, I _D =I _{AR} , V _{DD} =50 V)	850	mJ

 $^{2. \}quad I_{SD} \ \leq \ 17 \ A, \ di/dt \ \leq \ 200 \ A/\mu s, V_{DD} \ \leq \ V_{(BR)DSS}, \ T_{J} \ \leq \ T_{JMAX}$

Electrical characteristics STB21NK50Z

2 Electrical characteristics

(T_{CASE} = 25 °C unless otherwise specified)

Table 5. On/off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	I _D = 1mA, V _{GS} = 0	500			٧
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V _{DS} = Max rating, V _{DS} = Max rating @125 °C			1 50	μA μA
I _{GSS}	Gate body leakage current (V _{DS} = 0)	V _{GS} = ±20 V			±10	μΑ
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 100 \mu A$	3	3.75	4.5	٧
R _{DS(on)}	Static drain-source on resistance	V _{GS} = 10 V, I _D = 8.5 A		0.23	0.27	Ω

Table 6. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V _{DS} = 25 V, f=1 MHz, V _{GS} =0		2600 328 72		pF pF pF
C _{oss eq} ⁽¹⁾ .	Equivalent output capacitance	V _{GS} =0, V _{DS} =0 to 400 V		187		pF
Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	V_{DD} =400 V, I_{D} = 17 A V_{GS} =10 V (see Figure 15)		85 15.5 42	119	nC nC nC

^{1.} $C_{oss\ eq.}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}

Table 7. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)} t _r	Turn-on delay time Rise time	V_{DD} = 250 V, I_D = 8.5 A, R_G = 4.7 Ω , V_{GS} = 10 V (see Figure 16)		28 20		ns ns
t _{d(off)}	Turn-off delay time Fall time	V_{DD} = 250 V, I_D = 8.5 A, R_G = 4.7 Ω , V_{GS} =10 V (see Figure 16)		70 15		ns ns

Table 8. Gate-source Zener diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
BV _{GSO} ⁽¹⁾	Gate-source breakdown voltage	Igs=±1 mA (open drain)	30			V

The built-in back-to-back Zener diodes have specifically been designed to enhance not only the device's ESD capability, but also to make them safely absorb possible voltage transients that may occasionally be applied from gate to source. In this respect the Zener voltage is appropriate to achieve an efficient and cost-effective intervention to protect the device's integrity. These integrated Zener diodes thus avoid the usage of external components.

Table 9. Source drain diode

Symbol	Parameter	Test conditions	Min	Тур.	Max	Unit
I _{SD}	Source-drain current				17	Α
I _{SDM} ⁽¹⁾	Source-drain current (pulsed)				68	Α
V _{SD} ⁽²⁾	Forward on voltage	I _{SD} = 17 A, V _{GS} =0			1.6	V
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I_{SD} = 17 A, di/dt = 100 A/ μ s, V_{R} = 100 V (see Figure 16)		355 3.90 22		ns μC A
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I_{SD} = 17 A, di/dt = 100 A/ μ s, V_{R} = 100 V, Tj=150 °C (see Figure 16)		440 5.72 25		ns μC A

^{1.} Pulse width limited by safe operating area

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^{2.} Pulsed: pulse duration=300µs, duty cycle 1.5%

Electrical characteristics STB21NK50Z

2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

Figure 3. Thermal impedance

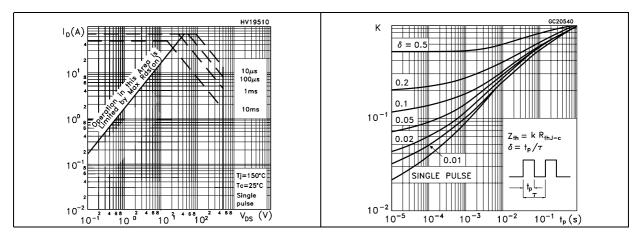


Figure 4. Output characteristics

Figure 5. Transfer characteristics

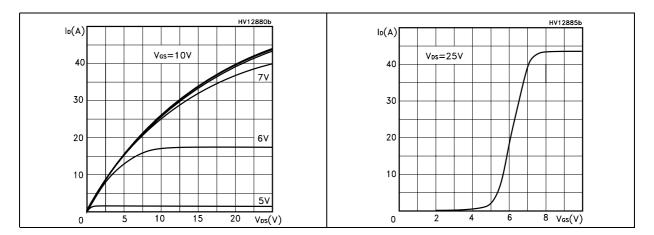
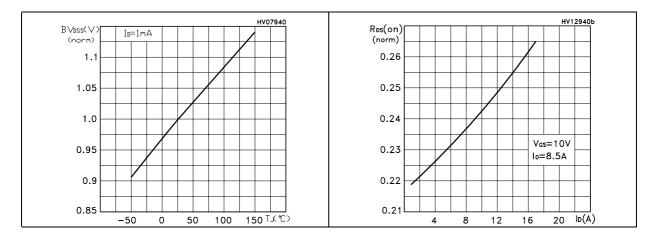


Figure 6. Normalized B_{VDSS} vs temperature

Figure 7. Static drain-source on resistance



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Figure 8. Gate charge vs gate-source voltage Figure 9. Capacitance variations

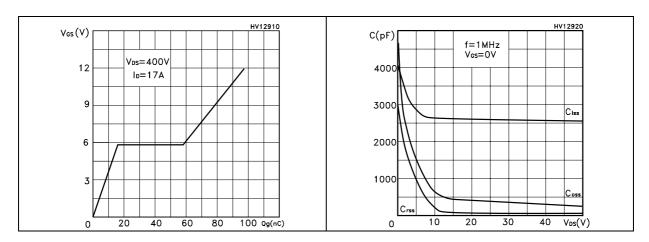


Figure 10. Normalized gate threshold voltage vs temperature

Figure 11. Normalized on resistance vs temperature

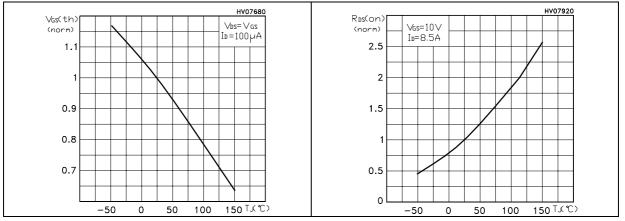
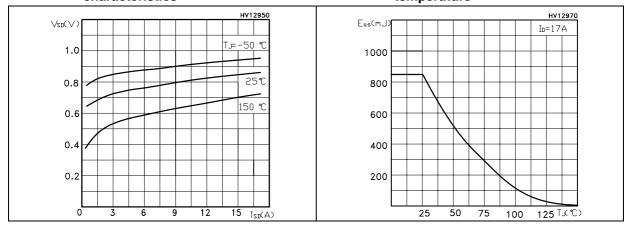


Figure 12. Source-drain diode forward characteristics

Figure 13. Maximum avalanche energy vs temperature



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Test circuits STB21NK50Z

3 Test circuits

Figure 14. Switching times test circuit for resistive load

Figure 15. Gate charge test circuit

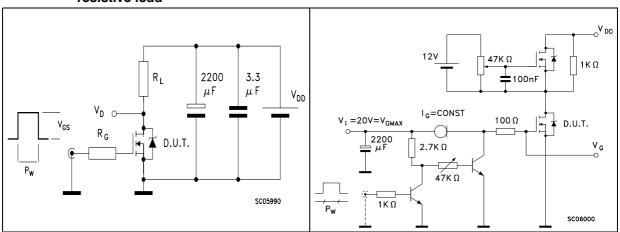


Figure 16. Test circuit for inductive load switching and diode recovery times

Figure 17. Unclamped Inductive load test circuit

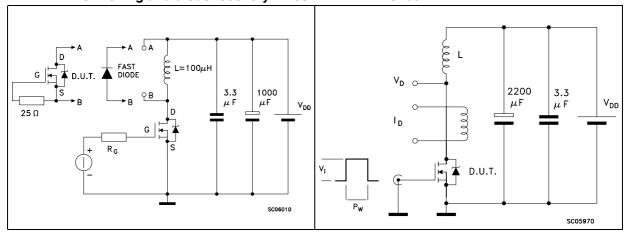
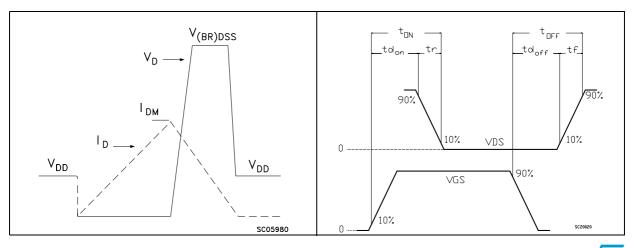


Figure 18. Unclamped inductive waveform

Figure 19. Switching time waveform



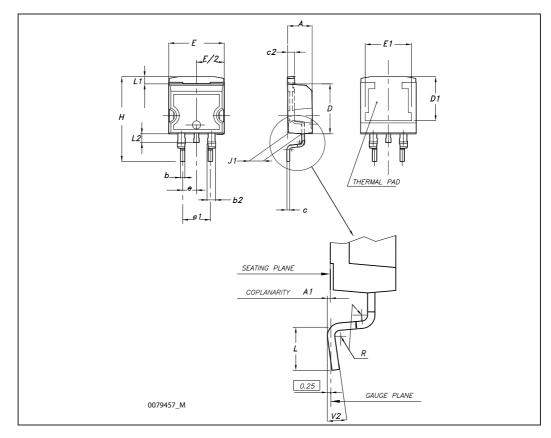
4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a lead-free second level interconnect. The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com

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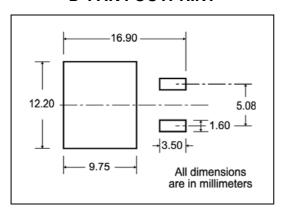
D²PAK (TO-263) mechanical data

D:		mm			inch	
Dim	Min	Тур	Max	Min	Тур	Max
Α	4.40		4.60	0.173		0.181
A1	0.03		0.23	0.001		0.009
b	0.70		0.93	0.027		0.037
b2	1.14		1.70	0.045		0.067
С	0.45		0.60	0.017		0.024
c2	1.23		1.36	0.048		0.053
D	8.95		9.35	0.352		0.368
D1	7.50			0.295		
E	10		10.40	0.394		0.409
E1	8.50			0.334		
е		2.54			0.1	
e1	4.88		5.28	0.192		0.208
Н	15		15.85	0.590		0.624
J1	2.49		2.69	0.099		0.106
L	2.29		2.79	0.090		0.110
L1	1.27		1.40	0.05		0.055
L2	1.30		1.75	0.051		0.069
R		0.4			0.016	
V2	0°		8°	0°		8°

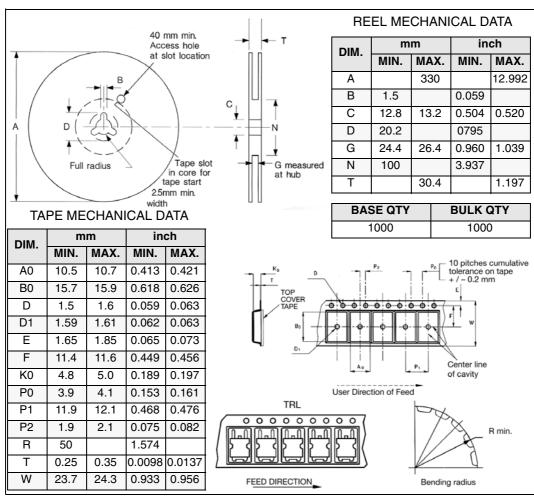


5 Packaging mechanical data

D²PAK FOOTPRINT



TAPE AND REEL SHIPMENT



Revision history STB21NK50Z

6 Revision history

Table 10. Document revision history

Date	Revision	Changes
16-Sep-2008	1	First issue

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